

# LT-1001 Series Precision Operational Amplifiers

## Features

- Ultra-low  $V_{OS}$  — 15  $\mu\text{V}$  max
- Ultra-low  $V_{OS}$  drift — 0.6  $\mu\text{V}/^\circ\text{C}$  max
- Low input bias current — 2 nA max
- High CMRR — 114 dB min
- High PSRR — 110 dB min
- Low noise — 0.3  $\mu\text{V}_{p-p}$  (0.1 to 10 Hz)
- Low power dissipation — 75 mW max
- High gain linearity
- LCC, SO-8, DIP and can packages

## Description

Designed for low level signal conditioning, instrumentation, and data conversion applications, the LT-1001 is a precision amplifier combining excellent dc input specifications with low input voltage noise. Advanced circuit design, wafer processing, and test methods all contribute to these well-balanced, mutually supporting input characteristics.

The circuit design uses special low-noise transistor geometries and careful thermal layout to achieve exceptionally low noise and linear

gain characteristics. A patented, proprietary test method which includes digital  $V_{OS}$  nulling after packaging as well as at wafer test tightens the distribution of this parameter such that the highest grade, the LT-1001AM, is specified at  $\pm 15 \mu\text{V}$  maximum. This low  $V_{OS}$ , along with extra-low power dissipation (which reduces warm-up drift), set the LT-1001 apart from similar precision op amp types.

## Ordering Information

Part Number	Package	Operating Temperature Range
LT-1001ACN	N	0°C to +70°C
LT-1001CN	N	0°C to +70°C
LT-1001ACM	M	0°C to +70°C
LT-1001CM	M	0°C to +70°C
LT-1001MT	T	-55°C to +125°C
LT-1001AMT/883B	T	-55°C to +125°C
LT-1001MD	D	-55°C to +125°C
LT-1001AMD/883B	D	-55°C to +125°C
LT-1001ML	L	-55°C to +125°C
LT-1001AML/883B	L	-55°C to +125°C

### Notes:

/883B suffix denotes Mil-Std-883, Level B processing

N = 8-lead plastic DIP

D = 8 lead ceramic DIP

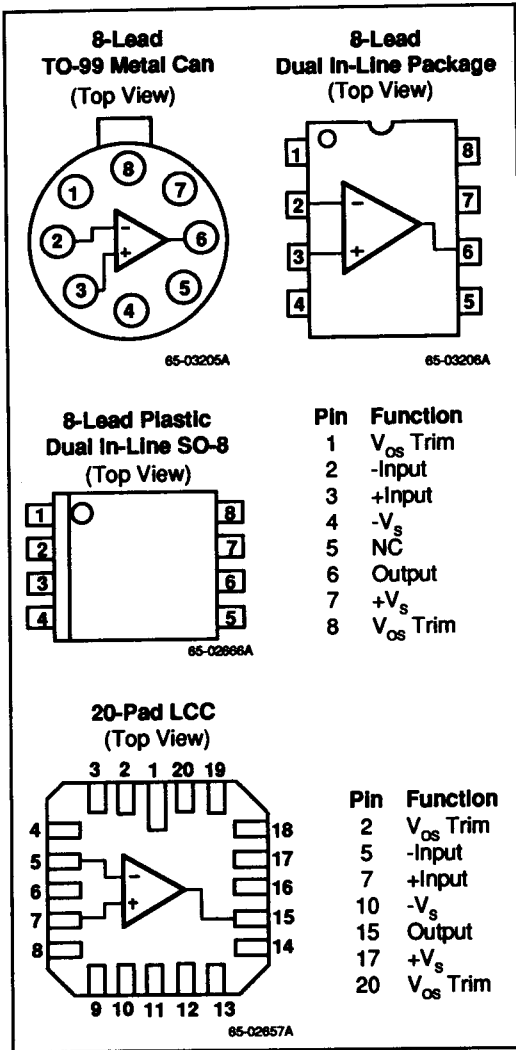
T = 8-lead metal can (TO-99)

L = 20-pad leadless chip carrier

M = 8-lead plastic SOIC

Contact a Raytheon sales office or representative for ordering information on special package/temperature range combinations.

### Connection Information



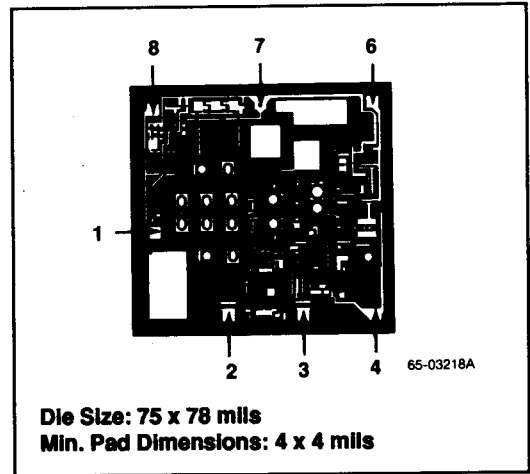
### Absolute Maximum Ratings

Supply Voltage	$\pm 22V$
Input Voltage*	$\pm 22V$
Differential Input Voltage	30V
Internal Power Dissipation**	500 mW
Output Short Circuit Duration	Indefinite
Storage Temperature Range	$-65^{\circ}C$ to $+150^{\circ}C$
Operating Temperature Range	
M Suffix	$-55^{\circ}C$ to $+125^{\circ}C$
C Suffix	$0^{\circ}C$ to $+70^{\circ}C$
Lead Soldering Temperature (SO-8; 10 sec)	$+260^{\circ}C$
Lead Soldering Temperature (DIP, LCC, TO-99; 60 sec)	$+300^{\circ}C$

\*For supply voltages less than  $\pm 22V$ , the absolute maximum input voltage is equal to the supply voltage.

\*\*Observe package thermal characteristics.

### Mask Pattern



### Thermal Characteristics

	20-Pad LCC	8-Lead Ceramic DIP	8-Lead TO-99 Metal Can	8-Lead Small Outline	8-Lead Plastic DIP
Max. Junction Temp.	175°C	175°C	175°C	125°C	125°C
Max. $P_D$ $T_A < 50^{\circ}C$	925 mW	833 mW	658 mW	300 mW	468 mW
Therm. Res $\theta_{JC}$	37°C/W	45°C/W	50°C/W	—	—
Therm. Res. $\theta_{JA}$	105°C/W	150°C/W	190°C/W	240°C/W	160°C/W
For $T_A > 50^{\circ}C$ Derate at	7.0 mW/°C	8.33 mW/°C	5.26 mW/°C	4.17 mW/°C	6.25 mW/°C

**Electrical Characteristics** ( $V_S = \pm 15V$  and  $T_A = +25^\circ C$  unless otherwise noted)

Parameters	Test Conditions	LT-1001A			LT-1001M/C			Units
		Min	Typ	Max	Min	Typ	Max	
Input Offset Voltage <sup>1</sup>	LT-1001AM/883B		7.0	15		18	60	$\mu V$
	LT-1001AC		10	25				
Long Term Input Offset Voltage Stability <sup>3,4</sup>			0.2	1.0		0.2	1.5	$\mu V/Mo$
Input Offset Current			0.3	2.0		0.4	3.8	nA
Input Bias Current			$\pm 0.5$	$\pm 2.0$		$\pm 1.0$	$\pm 4.0$	nA
Input Noise Voltage <sup>2</sup>	0.1 Hz to 10 Hz		0.35	0.6		0.35	0.6	$\mu V_{p-p}$
Input Noise Voltage Density <sup>2,5</sup>	$f_O = 10$ Hz		10.3	18		10.3	18	$\frac{nV}{\sqrt{Hz}}$
	$f_O = 100$ Hz		10	13		10	13	
	$f_O = 1000$ Hz		9.6	11		9.6	11	
Input Noise Current <sup>2</sup>	0.1 Hz to 10 Hz		14	30		14	30	$pA_{p-p}$
Input Noise Current Density <sup>5</sup>	$f_O = 10$ Hz		0.32	0.8		0.32	0.8	$\frac{pA}{\sqrt{Hz}}$
	$f_O = 100$ Hz		0.14	0.23		0.14	0.23	
	$f_O = 1000$ Hz		0.12	0.17		0.12	0.17	
Input Resistance (Diff. Mode) <sup>3</sup>		30	100		15	80		$M\Omega$
Input Resistance (Com. Mode)			200			200		$G\Omega$
Input Voltage Range		$\pm 13$	$\pm 14$		$\pm 13$	$\pm 14$		V
Common Mode Rejection Ratio	$V_{CM} = \pm 13V$	114	126		110	126		dB
Power Supply Rejection Ratio	$V_S = \pm 3V$ to $\pm 18V$	110	123		106	123		dB
Large Signal Voltage Gain	$R_L \geq 2$ k $\Omega$ , $V_O = \pm 12V$	450	2000		400	2000		V/mV
	$R_L \geq 1$ k $\Omega$ , $V_O = \pm 10V$	300	1000		250	1000		
Output Voltage Swing	$R_L \geq 2$ k $\Omega$	$\pm 13$	$\pm 14$		$\pm 13$	$\pm 14$		V
	$R_L \geq 1$ k $\Omega$	$\pm 12$	$\pm 13.5$		$\pm 12$	$\pm 13.5$		
Slew Rate	$R_L \geq 2$ k $\Omega$	0.1	0.3		0.1	0.3		$V/\mu S$
Unity Gain Bandwidth	$A_{VCL} = +1.0$	0.4	0.8		0.4	0.8		MHz
Open Loop Output Resistance	$V_O = 0$ , $I_O = 0$		60			60		$\Omega$
Power Consumption	$V_S = \pm 15V$ , $R_L = \infty$		50	75		50	80	mW
	$V_S = \pm 3V$ , $R_L = \infty$		4.0	6.0		4.0	8.0	
Offset Adjustment Range	$R_P = 20$ k $\Omega$		$\pm 4.0$			$\pm 4.0$		mV

**Notes:**

1. Input Offset Voltage measurements are performed by automated test equipment approximately 0.5 seconds after application of power. LT1001AM/883B and LT-1001AC grades in hermetic packages are measured after the device is fully warmed up.
2. This parameter is tested on a sample basis only.
3. This parameter is guaranteed by design.
4. Long Term Input Offset Voltage Stability refers to the average trend line of  $V_{OS}$  vs. Time over extended periods after the first 30 days of operation. Excluding the initial hour of operation, changes in  $V_{OS}$  during the first 30 operating days are typically 2.5  $\mu V$ .
5. 10 Hz input noise voltage density is sample tested on every lot. Devices 100% tested at 10 Hz are available on request.

**Electrical Characteristics** ( $V_S = \pm 15V$  and  $-55^\circ C \leq T_A \leq +125^\circ C$  unless otherwise noted)

Parameters	Test Conditions	LT-1001AM/883B			LT-1001M			Units
		Min	Typ	Max	Min	Typ	Max	
Input Offset Voltage <sup>1</sup>			25	60		45	160	$\mu V$
Average Input Offset Voltage Drift Without External Trim <sup>2</sup>			0.2	0.6		0.3	1.0	$\mu V/^\circ C$
With External Trim <sup>3</sup>	$R_P = 20\text{ k}\Omega$		0.2	0.6		0.3	1.0	
Input Offset Current			0.8	4.0		1.2	7.6	nA
Average Input Offset Current Drift <sup>2</sup>			5.0	25		8.0	50	$\text{pA}/^\circ C$
Input Bias Current			$\pm 1.0$	$\pm 4.0$		$\pm 1.5$	$\pm 8.0$	nA
Average Input Bias Current Drift <sup>2</sup>			8.0	25		13	50	$\text{pA}/^\circ C$
Input Voltage Range		$\pm 13$	$\pm 13.5$		$\pm 13$	$\pm 13.5$		V
Common Mode Rejection Ratio	$V_{CM} = \pm 13V$	110	123		106	123		dB
Power Supply Rejection Ratio	$V_S = \pm 3.0V$ to $\pm 18V$	104	117		100	117		dB
Large Signal Voltage Gain	$R_L \geq 2\text{ k}\Omega$ , $V_O = \pm 10V$	300	600		200	600		V/mV
Output Voltage Swing	$R_L \geq 2\text{ k}\Omega$	$\pm 12.5$	$\pm 13$		$\pm 12$	$\pm 13$		V
Power Consumption	$R_L = \infty$		60	90		60	100	mW

See notes on page 3.

**Electrical Characteristics** ( $V_S = \pm 15V$  and  $0^\circ C \leq T_A \leq +70^\circ C$  unless otherwise noted)

Parameters	Test Conditions	LT-1001AC			LT-1001C			Units
		Min	Typ	Max	Min	Typ	Max	
Input Offset Voltage <sup>1</sup>			20	60		30	110	$\mu V$
Average Input Offset Voltage Drift Without External Trim <sup>2</sup>			0.2	0.6		0.3	1.0	$\mu V/^\circ C$
With External Trim <sup>3</sup>	$R_P = 20\text{ k}\Omega$		0.2	0.6		0.3	1.0	
Input Offset Current			0.5	3.5		1.6	8.0	nA
Average Input Offset Current Drift <sup>2</sup>			8.0	35		12	50	$\text{pA}/^\circ C$
Input Bias Current			$\pm 0.7$	$\pm 3.5$		$\pm 1.0$	$\pm 5.5$	nA
Average Input Bias Current Drift <sup>2</sup>			13	35		18	50	$\text{pA}/^\circ C$
Input Voltage Range		$\pm 13$	$\pm 13.5$		$\pm 13$	$\pm 13.5$		V
Common Mode Rejection Ratio	$V_{CM} = \pm 13V$	110	123		106	120		dB
Power Supply Rejection Ratio	$V_S = \pm 3.0V$ to $\pm 18V$	106	120		103	120		dB
Large Signal Voltage Gain	$R_L \geq 2\text{ k}\Omega$ , $V_O = \pm 10V$	300	600		250	600		V/mV
Output Voltage Swing	$R_L \geq 2\text{ k}\Omega$	$\pm 12.5$	$\pm 13.5$		$\pm 12.5$	$\pm 13.5$		V
Power Consumption	$R_L = \infty$		60	85		60	90	mW

See notes on page 3.

## Applications Information

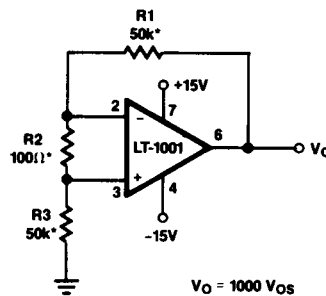
The LT-1001 series units may be inserted directly into OP-07, OP-05, 725, 108A or 101A sockets with or without removal of external frequency compensation or nulling components. The LT-1001 can also be used in 741 applications provided that the nulling circuitry is removed.

Unless proper care is exercised, thermocouple effects caused by temperature gradients across

dissimilar metals at the contacts to the input terminals, can exceed the inherent drift of the amplifier. Air currents over device leads should be minimized, package leads should be short, and the two input leads should be as close together as possible and maintained at the same temperature.

Input bias currents may flow either into or out of the input terminals, depending on the value of  $I_{OS}$ .

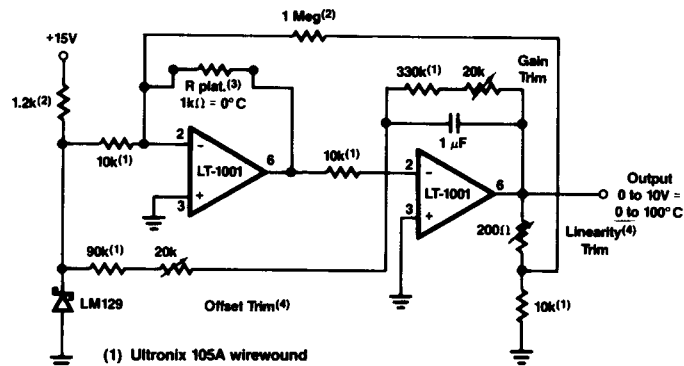
## Typical Applications



\*Resistors must have low thermoelectric potential.

65-03787A

### Test Circuit for Offset Voltage and Its Drift With Temperature



- (1) Ultronix 105A wirewound
- (2) 1% film
- (3) Platinum RTD 118MF (Rosemount, Inc.)
- (4) Trim sequence:  
 trim offset ( $0^\circ\text{C} = 1000.0(1)$ ),  
 trim linearity ( $35^\circ\text{C} = 1138.7(1)$ ),  
 trim gain ( $100^\circ\text{C} = 1392.6(1)$ ).  
 Repeat until all three points are fixed with  $\pm 0.025^\circ\text{C}$ .

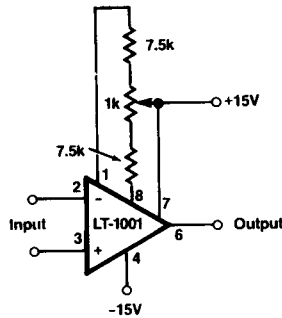
65-03788A

### Linearized Platinum Resistance Thermometer With $\pm 0.025^\circ\text{C}$ Accuracy Over 0 to $100^\circ\text{C}$

### Offset Voltage Adjustment

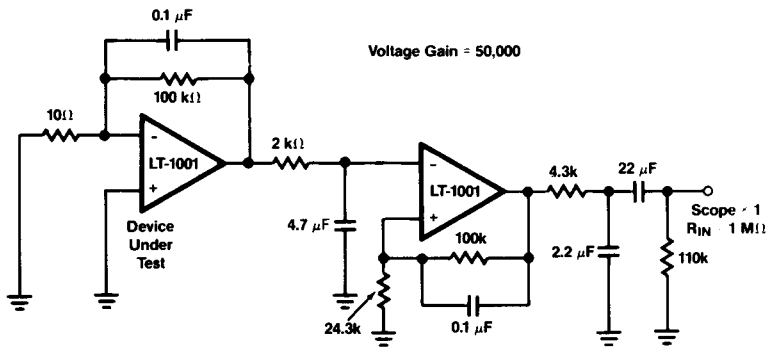
The input offset voltage of the LT-1001, and its drift with temperature, are permanently trimmed at wafer test to a low level. However, if further adjustment of  $V_{OS}$  is necessary, nulling with a 10k or 20k potentiometer will not degrade drift with temperature. Trimming to a value other than zero creates a drift of  $(V_{OS}/300) \mu V/^\circ C$ ,

e.g., if  $V_{OS}$  is adjusted to  $300 \mu V$ , the change in drift will be  $1 \mu V/^\circ C$ . The adjustment range with a 10k or 20k pot is approximately 4.0 mV. If less adjustment range is needed, the sensitivity and resolution of the nulling can be improved by using a smaller pot in conjunction with fixed resistors. The example below has an approximate null range of  $\pm 100 \mu V$ .



65-03789A

### Improved Sensitivity Adjustment

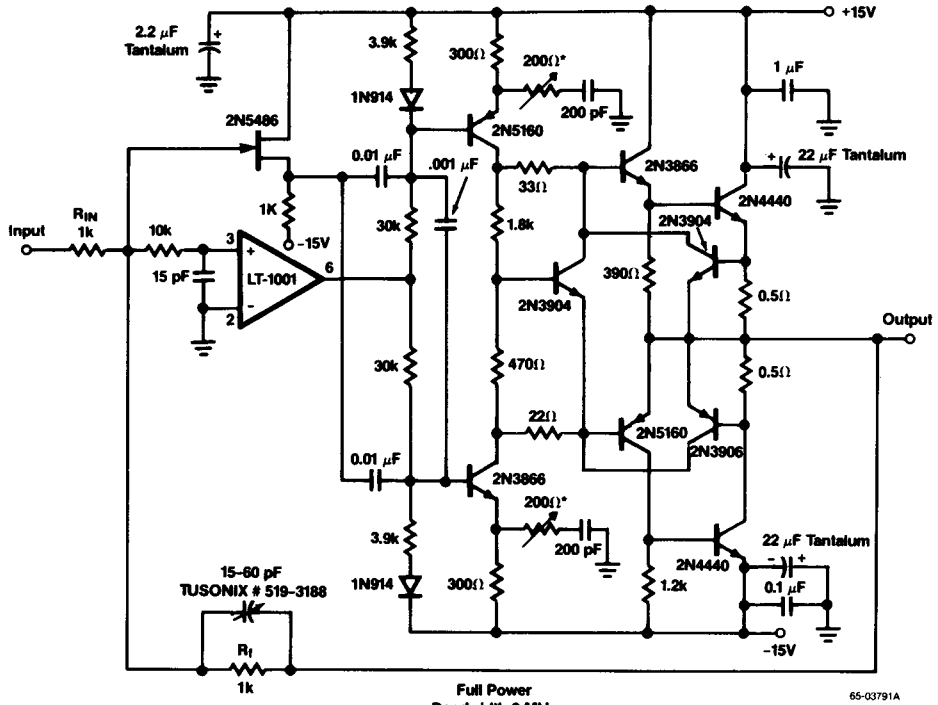


- (1) Peak-to-peak noise is measured in a 10-second interval
- (2) The device under test should be warmed up for 3 minutes and shielded from air currents.

### 0.1 Hz to 10 Hz Noise Test Circuit

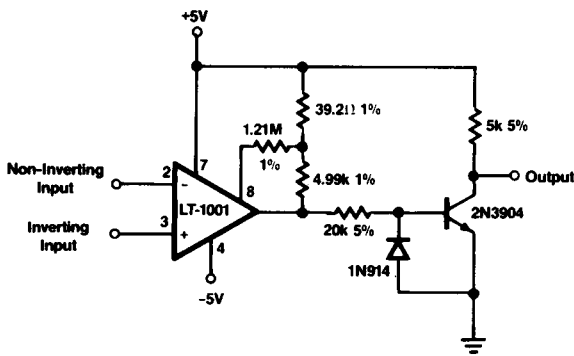
65-03790A

Typical Applications (Continued)



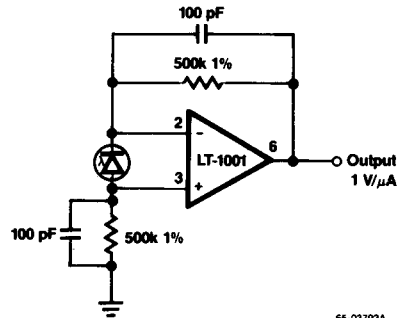
\*Adjust for best squarewave at output.

DC Stabilized — 1000 V/μS Op Amp



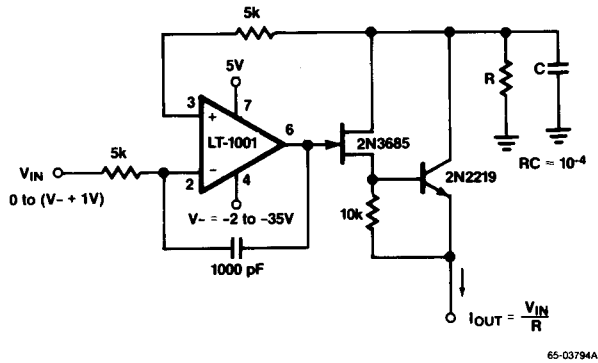
Positive feedback to one of the nulling terminals creates 5μ to 20 μV of hysteresis. Input offset voltage is typically changed by less than 5 μV due to the feedback.

Microvolt Comparator With TTL Output

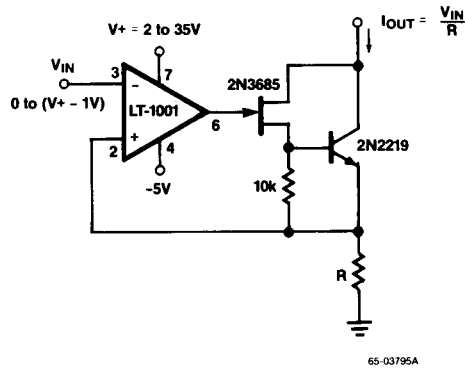


Photodiode Amplifier

Typical Applications (Continued)



Precision Current Source



Precision Current Sink



# Schematic Diagram

